NTR3A30PZ

[MOSFET](#) – Power, Single P-Channel, SOT-23, 2.4 x 2.9 x 1.0 mm

-20 V, -5.5 A

ON Semiconductor®

Features

- Low $R_{DS(on)}$ Solution in 2.4 mm x 2.9 mm Package
- ESD Diode−Protected Gate
- These Devices are Pb−Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- High Side Load Switch
- Battery Switch
- Optimized for Power Management Applications for Portable Products, such as Smart Phones, Media Tablets, PMP, DSC, GPS, and Others

$V_{(BR)DSS}$	$R_{DS(on)}$ Max	I_D MAX
−20 V	38 mΩ @ −4.5 V	−5.5 A
	50 mΩ @ −2.5 V	
	73 mΩ @ −1.8 V	

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain−to−Source Voltage			V_{DSS}	−20	V
Gate−to−Source Voltage			V_{GS}	±8	V
Drain Current (Note 1) Drain Current (Note 1)	Steady State	T_A = 25°C	I_D	−3.0	A
		T_A = 85°C		−2.2	
	$t \le 5$ s	T_A = 25°C		−5.5	
Power Dissipation (Note 1)	Steady State	T_A = 25°C	P_D	0.48	W
	$t \le 5$ s			1.58	
Pulsed Drain Current	t_p = 10 μs		I_{DM}	−9.1	A
Operating Junction and Storage Temperature			T_J, T_{STG}	−55 to 150	°C
ESD HBM, JESD22−A114			V_{ESD}	2000	V
Source Current (Body Diode) (Note 2)			I_S	−0.48	A
Lead Temperature for Soldering Purposes (1/8 in from case for 10 s)			T_L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction−to−Ambient – Steady State (Note 1)	$R_{\theta JA}$	260	°C/W
Junction−to−Ambient – $t \le 5$ s (Note 1)	$R_{\theta JA}$	79	

1. Surface−mounted on FR4 board using 1 in sq. pad size (Cu area = 1.127 in sq. [2 oz] including traces).
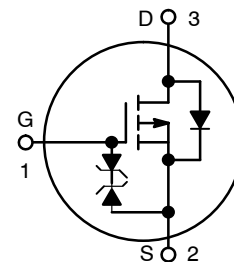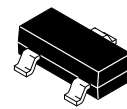2. Pulse Test: pulse width ≤ 300 ms, duty cycle ≤ 2%.

P−Channel MOSFET

MARKING DIAGRAM & PIN ASSIGNMENT

SOT−23 CASE 318 STYLE 21
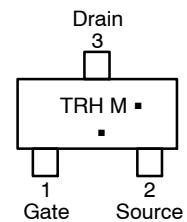
TRH	= Specific Device Code
M	= Date Code*
▪	= Pb−Free Package

(Note: Microdot may be in either location)

*Date Code orientation may vary depending upon manufacturing location.

ORDERING INFORMATION

Device	Package	Shipping†
NTR3A30PZT1G	SOT−23 (Pb−Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

NTR3A30PZ

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Typ	Max	Unit
OFF CHARACTERISTICS							
Drain−to−Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0 V, I_D = 250 μA		−20			V
Drain−to−Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$	I_D = −250 μA, ref to 25°C			10.5		mV/°C
Zero Gate Voltage Drain Current	I_{DSS}	V_{GS} = 0 V, V_{DS} = −20 V	T_J = 25°C			−1	μA
Gate−to−Source Leakage Current	I_{GSS}	V_{DS} = 0 V, V_{GS} = ±5 V				±10	μA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	$V_{GS(TH)}$	V_{GS} = V_{DS}, I_D = −250 μA		−0.4	−0.65	−1.0	V
Negative Threshold Temperature Coefficient	$V_{GS(TH)}/T_J$				10.5		mV/°C
Drain−to−Source On Resistance	$R_{DS(on)}$	V_{GS} = −4.5 V	I_D = −3 A		31	38	mΩ
		V_{GS} = −2.5 V	I_D = −2.5 A		36	50	
		V_{GS} = −1.8 V	I_D = −1.5 A		51	73	
Forward Transconductance	g_{FS}	V_{DS} = −5 V, I_D = −3 A			30		S
CHARGES AND CAPACITANCES							
Input Capacitance	C_{iss}	V_{GS} = 0 V, f = 1.0 MHz, V_{DS} = −15 V			1651		pF
Output Capacitance	C_{oss}				148		
Reverse Transfer Capacitance	C_{rss}				129		
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = −4.5 V, V_{DS} = −15 V, I_D = −3 A			17.6		nC
Threshold Gate Charge	$Q_{G(TH)}$				0.7		
Gate−to−Source Charge	Q_{GS}				2.4		
Gate−to−Drain Charge	Q_{GD}				4.9		
SWITCHING CHARACTERISTICS (Note 4)							
Turn−On Delay Time	$t_{d(on)}$	V_{GS} = −4.5 V, V_{DS} = −15 V, I_D = −3 A, R_G = 6.0 Ω			100		ns
Rise Time	t_r				208		
Turn−Off Delay Time	$t_{d(off)}$				1043		
Fall Time	t_f				552		
DRAIN−SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V_{SD}	V_{GS} = 0 V, I_S = −0.4 A	T_J = 25°C		0.65	1.0	V
			T_J = 125°C		0.47		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
3. Pulse Test: pulse width ≤ 300 ms, duty cycle ≤ 2%.
4. Switching characteristics are independent of operating junction temperatures.

NTR3A30PZ
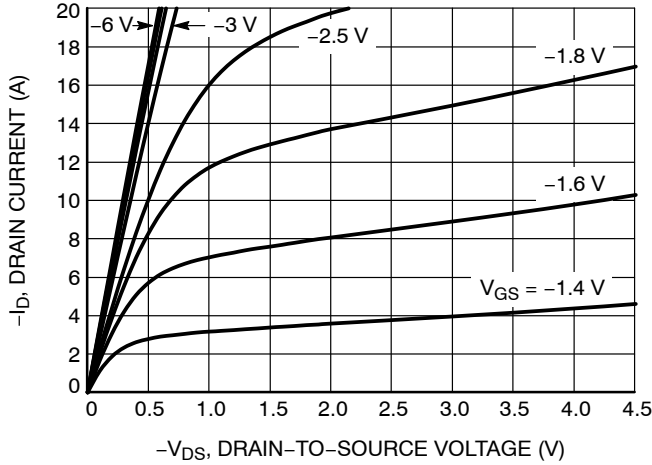
TYPICAL CHARACTERISTICS

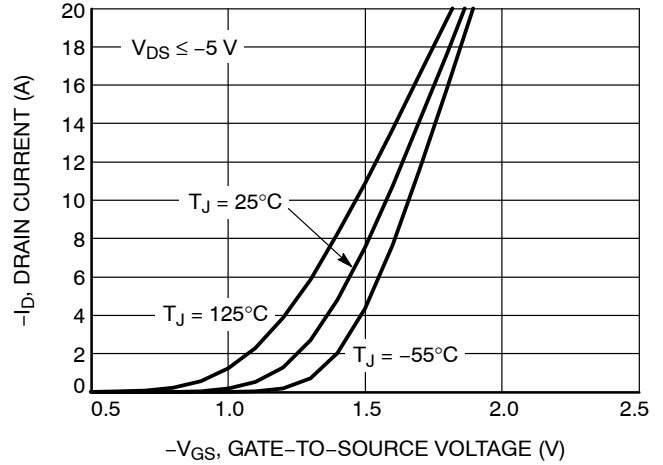

Figure 1. On−Region Characteristics
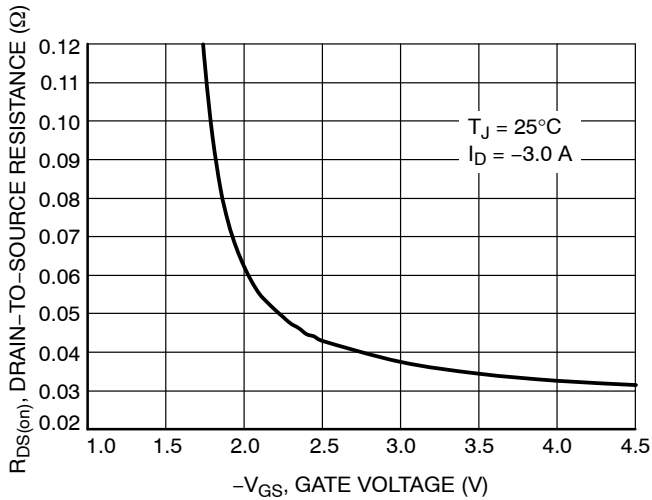

Figure 2. Transfer Characteristics

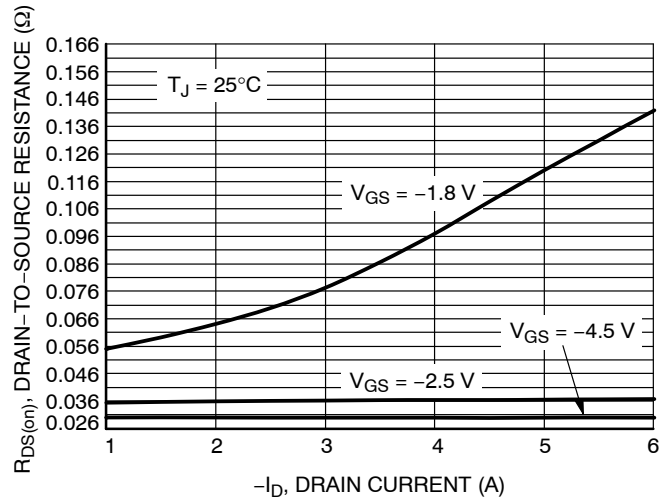Figure 3. On−Resistance vs. Gate−to−Source Voltage

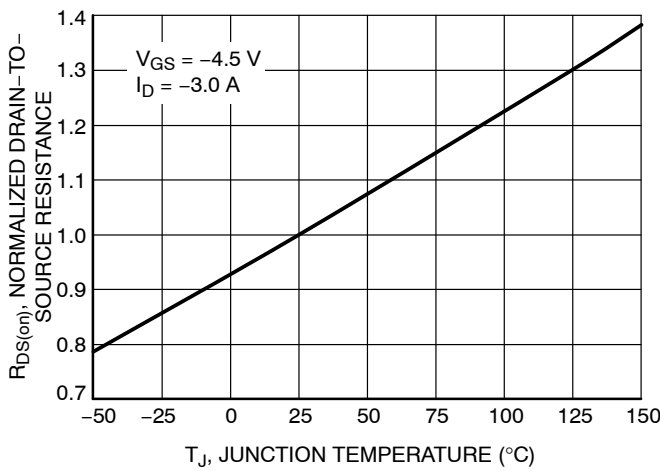
Figure 4. On−Resistance vs. Drain Current and Gate Voltage

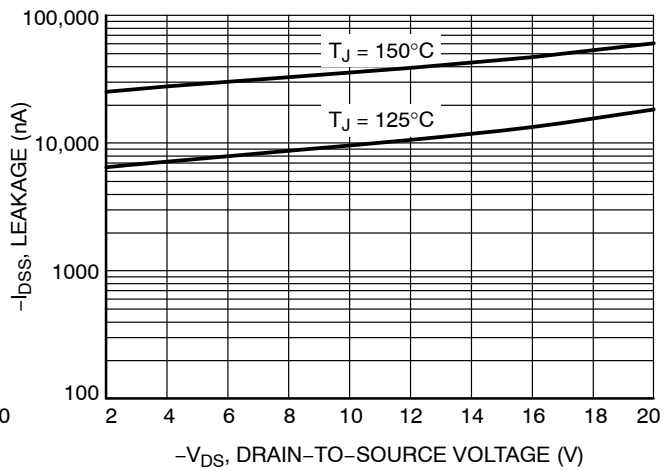Figure 5. On−Resistance Variation with Temperature

Figure 6. Drain−to−Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS
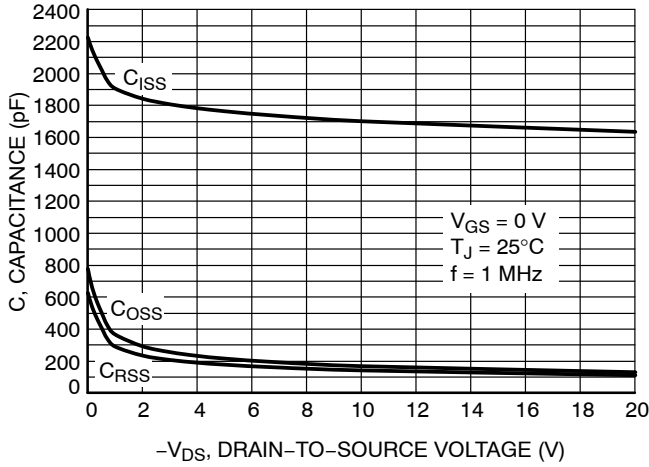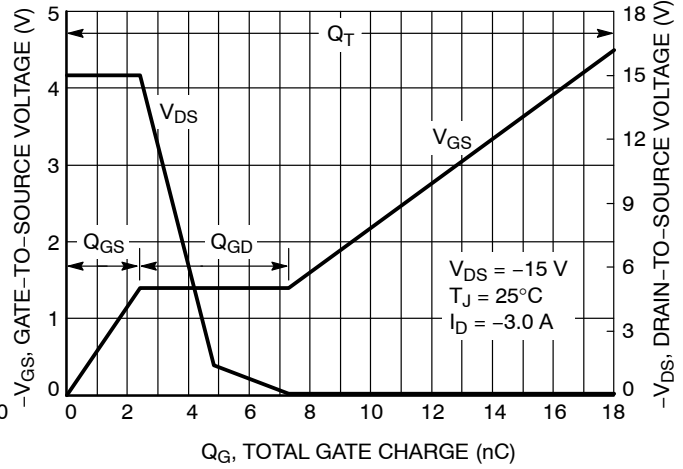

Figure 7. Capacitance Variation

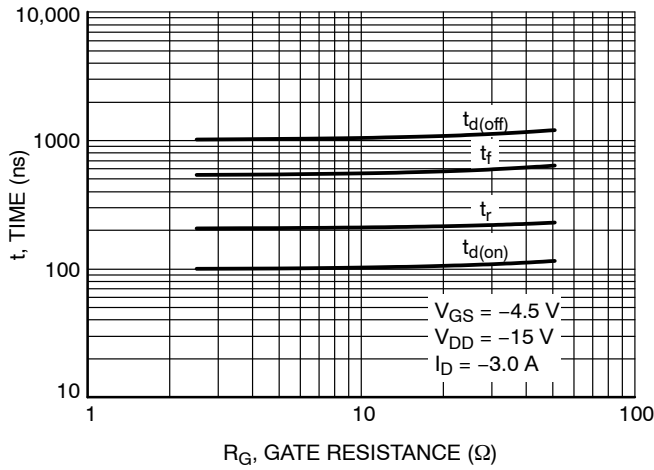**Figure 8. Gate−to−Source and
Drain−to−Source Voltage vs. Total Charge**

**Figure 9. Resistive Switching Time Variation
vs. Gate Resistance**
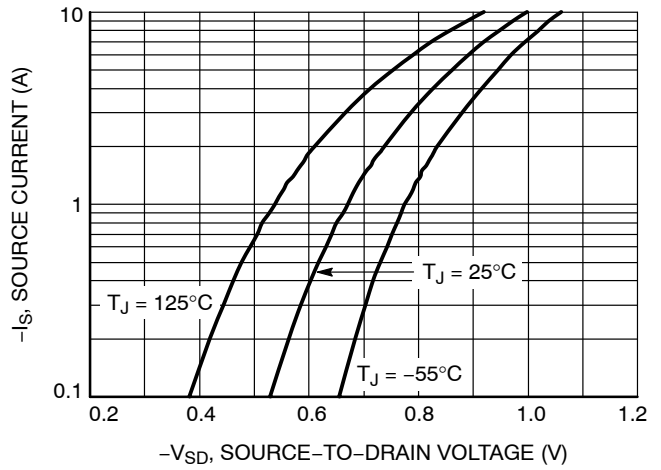
Figure 10. Diode Forward Voltage vs. Current
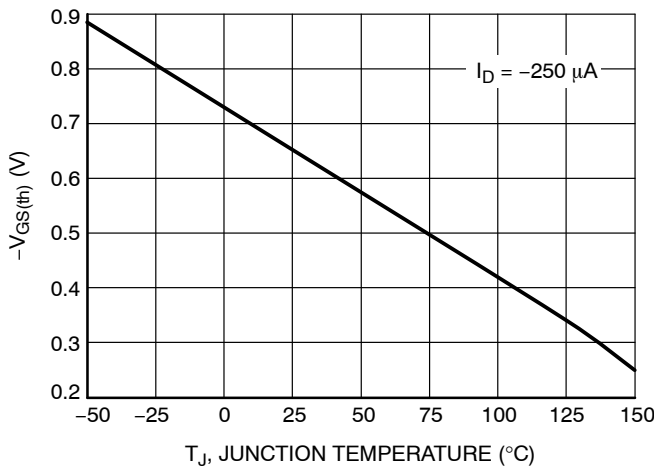
Figure 11. Threshold Voltage
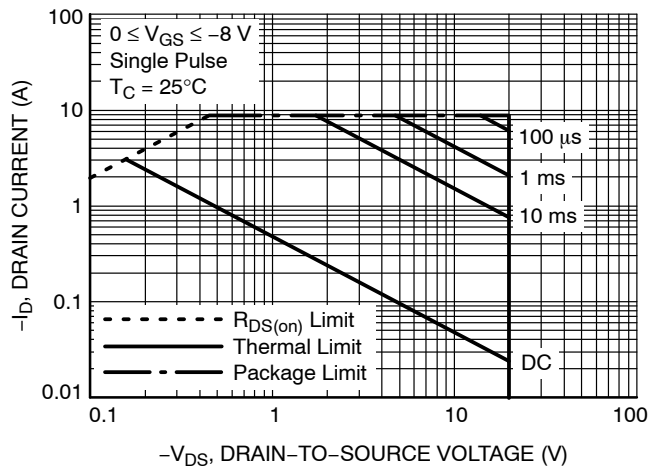
**Figure 12. Maximum Rated Forward Biased
Safe Operating Area**

TYPICAL CHARACTERISTICS

Figure 13. FET Thermal Response
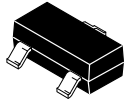
SOT−23 (TO−236)
CASE 318
ISSUE AT

DATE 01 MAR 2023

SCALE 4:1
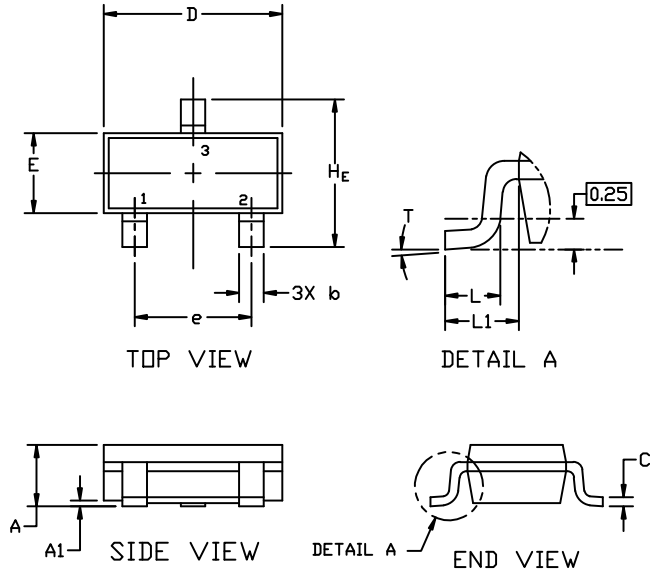
NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M,1994.

2. CONTROLLING DIMENSION: MILLIMETERS

3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF THE BASE MATERIAL.

4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

TOP VIEW

DETAIL A

SIDE VIEW

DETAIL A   END VIEW

DIM	MILLIMETERS			INCHES		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	0.89	1.00	1.11	0.035	0.039	0.044
A1	0.01	0.06	0.10	0.000	0.002	0.004
b	0.37	0.44	0.50	0.015	0.017	0.020
c	0.08	0.14	0.20	0.003	0.006	0.008
D	2.80	2.90	3.04	0.110	0.114	0.120
E	1.20	1.30	1.40	0.047	0.051	0.055
e	1.78	1.90	2.04	0.070	0.075	0.080
L	0.30	0.43	0.55	0.012	0.017	0.022
L1	0.35	0.54	0.69	0.014	0.021	0.027
H$_E$	2.10	2.40	2.64	0.083	0.094	0.104
T	0°	---	10°	0°	---	10°

GENERIC MARKING DIAGRAM*

XXXM▪

1
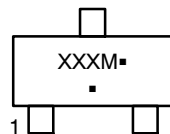
XXX = Specific Device Code
M   = Date Code
▪   = Pb−Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.
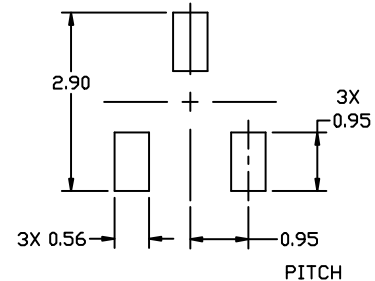
RECOMMENDED MOUNTING FOOTPRINT

✳ For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

STYLES ON PAGE 2

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SOT−23 (TO−236)
CASE 318
ISSUE AT

DATE 01 MAR 2023

STYLE 1 THRU 5:
CANCELLED

STYLE 6:
PIN 1. BASE
2. EMITTER
3. COLLECTOR

STYLE 7:
PIN 1. EMITTER
2. BASE
3. COLLECTOR

STYLE 8:
PIN 1. ANODE
2. NO CONNECTION
3. CATHODE

STYLE 9:
PIN 1. ANODE
2. ANODE
3. CATHODE

STYLE 10:
PIN 1. DRAIN
2. SOURCE
3. GATE

STYLE 11:
PIN 1. ANODE
2. CATHODE
3. CATHODE−ANODE

STYLE 12:
PIN 1. CATHODE
2. CATHODE
3. ANODE

STYLE 13:
PIN 1. SOURCE
2. DRAIN
3. GATE

STYLE 14:
PIN 1. CATHODE
2. GATE
3. ANODE

STYLE 15:
PIN 1. GATE
2. CATHODE
3. ANODE

STYLE 16:
PIN 1. ANODE
2. CATHODE
3. CATHODE

STYLE 17:
PIN 1. NO CONNECTION
2. ANODE
3. CATHODE

STYLE 18:
PIN 1. NO CONNECTION
2. CATHODE
3. ANODE

STYLE 19:
PIN 1. CATHODE
2. ANODE
3. CATHODE−ANODE

STYLE 20:
PIN 1. CATHODE
2. ANODE
3. GATE

STYLE 21:
PIN 1. GATE
2. SOURCE
3. DRAIN

STYLE 22:
PIN 1. RETURN
2. OUTPUT
3. INPUT

STYLE 23:
PIN 1. ANODE
2. ANODE
3. CATHODE

STYLE 24:
PIN 1. GATE
2. DRAIN
3. SOURCE

STYLE 25:
PIN 1. ANODE
2. CATHODE
3. GATE

STYLE 26:
PIN 1. CATHODE
2. ANODE
3. NO CONNECTION

STYLE 27:
PIN 1. CATHODE
2. CATHODE
3. CATHODE

STYLE 28:
PIN 1. ANODE
2. ANODE
3. ANODE

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ADDITIONAL INFORMATION

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